

UTCLD1117 LINEAR INTEGRATED CIRCUIT

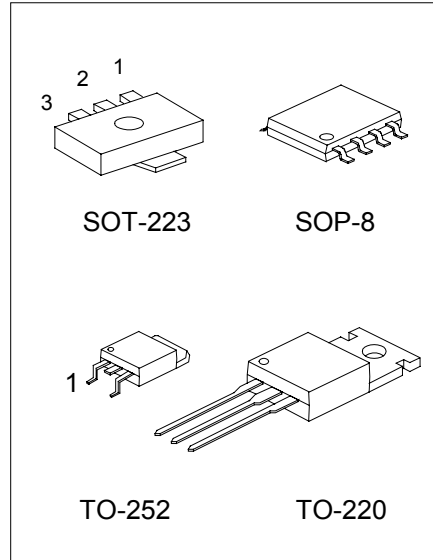
LOW DROP FIXED AND ADJUSTABLE POSITIVE VOLTAGE REGULATORS

DESCRIPTION

The UTC LD1117 is a LOW DROP Voltage Regulator able to provide up to 800mA of Output Current, available even in adjustable version ($V_{ref}=1.25V$). Concerning fixed versions, are offered the following Output Voltages: 2.5V, 2.85V, 3.0V, 3.0V and 5.0V. The 2.85V type is ideal for SCSI-2 lines active termination. The device is supplied in: SOT-223, TO-252, SOP8 and TO-220. The SOT-223 and TO-252 surface mount packages optimize the thermal characteristics even offering a relevant space saving effect. High efficiency is assured by NPN pass transistor. In fact in the case, unlike than PNP one, the Quiescent Current flows mostly into the load. Only a very common 10 μ F minimum capacitor is needed for stability. On chip trimming allows the regulator to reach a very tight output voltage tolerance, within $\pm 1\%$ at 25°C. The ADJUSTABLE LD1117 is pin to pin compatible with the other standard Adjustable voltage regulators maintaining the better performances in terms of Drop and Tolerance.

FEATURES

- *Low dropout voltage (1V Typ.)
- *2.85V device performances are suitable for SCSI-2 active termination
- *Output current up to 800mA
- *Fixed output voltage of: 2.5V, 2.85V, 3.0V, 3.3V, 5.0V
- *Adjustable version availability ($V_{ref}=1.25V$)
- *Internal current and thermal limit
- *Available in $\pm 1\%$ (at 25°C) and 2% in all temperature range
- *Supply voltage rejection: 75dB (TYP)
- *Temperature range: 0°C to 125°C



SOT-223 1: GND; 2: Vout; 3: Vin

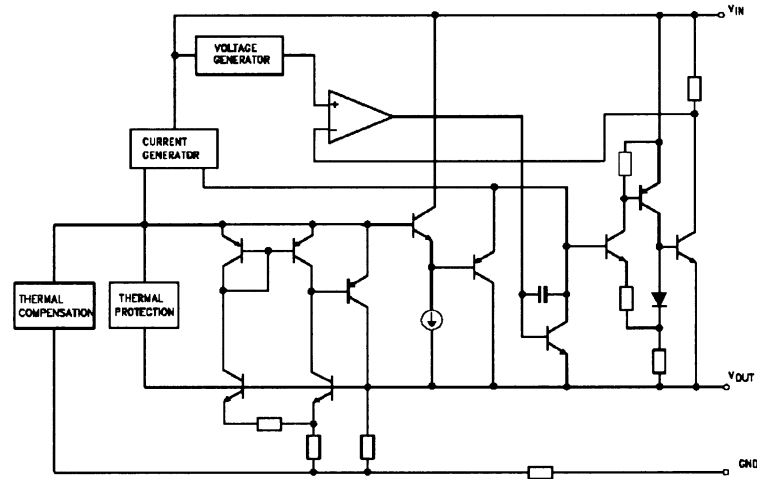
SOP-8 1: GND; 2,3,6,7: Vout; 4: Vin;
5,8: NC

TO-220 1: GND; 2: Vout; 3: Vin

TO-252 1: GND; 2: Vout; 3: Vin

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BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	VALUE	UNIT
DC Input Voltage	V_{IN}	15	V
Power Dissipation	P_{tot}	12	W
Storage temperature	T_{stg}	-65 ~ +150	°C
Operating Junction Temperature	T_{op}	0 ~ +125	°C

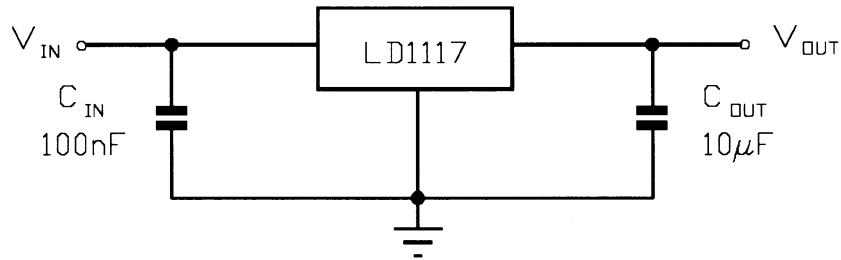
Note: Absolute Maximum Ratings are those value beyond which damage to the device may occur. Functional operation under there condition is not implied. Over the above suggested Max Power Dissipation a Short Circuit could definitively damage the device.

THERMAL DATA

PARAMETER	SYMBOL	VALUE	UNIT
Thermal Resistance Junction-case	Rth-case		
SOT-223		15	°C/W
SOP-8		20	°C/W
TO-252		8	°C/W
TO-220		3	°C/W
Thermal Resistance Junction-ambient	Rthj-amb		
TO-220		50	°C/W

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APPLICATION CIRCUIT



UTC LD1117-2.5 ELECTRICAL CHARACTERISTICS

(refer to the test circuits, T_j=0 to 125°C, C_o=10μF unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Output Voltage	V _o	V _{in} =4.5V, I _o =10mA, T _j =25°C	2.475	2.500	2.525	V
Output Voltage	V _o	I _o =0 to 800mA, V _{in} =3.9 to 10V	2.450		2.550	V
Line Regulation	ΔV _o	V _{in} =3.9 to 10V, I _o =0mA		1	6	mV
Load Regulation	ΔV _o	V _{in} =3.9V, I _o =0 to 800mA		1	10	mV
Temperature stability	ΔV _o			0.5		%
Long Term Stability	ΔV _o	1000 hrs, T _j =125°C		0.3		%
Operating Input Voltage	V _{in}	I _o =100mA			15	V
Quiescent Current	I _d	V _{in} ≤10V		5	10	mA
Output Current	I _o	V _{in} =7.5V, T _j =25°C	800	950	1200	mA
Output Noise Voltage	e _N	B=10Hz to 10KHz, T _j =25°C		100		μV
Supply Voltage Rejection	SVR	I _o =40mA, f=120Hz, T _j =25°C, V _{in} =5.5V, V _{ripple} =1Vpp	60	75		dB
Dropout Voltage	V _d	I _o =100mA		1.00	1.10	V
		I _o =500mA		1.05	1.15	V
		I _o =800mA		1.10	1.20	V
Thermal Regulation		T _a =25°C, 30ms Pulse		0.01	0.10	%/W

UTC LD1117-2.8 ELECTRICAL CHARACTERISTICS

(refer to the test circuits, T_j=0 to 125°C, C_o=10μF unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Output Voltage	V _o	V _{in} =4.85V, I _o =10mA, T _j =25°C	2.82	2.85	2.88	V
Output Voltage	V _o	I _o =0 to 800mA, V _{in} =4.25 to 10V	2.79		2.91	V
Line Regulation	ΔV _o	V _{in} =4.25 to 10V, I _o =0mA		1	6	mV
Load Regulation	ΔV _o	V _{in} =4.25V, I _o =0 to 800mA		1	10	mV
Temperature stability	ΔV _o			0.5		%
Long Term Stability	ΔV _o	1000 hrs, T _j =125°C		0.3		%
Operating Input Voltage	V _{in}	I _o =100mA			15	V
Quiescent Current	I _d	V _{in} ≤10V		5	10	mA
Output Current	I _o	V _{in} =7.85V, T _j =25°C	800	950	1200	mA
Output Noise Voltage	e _N	B=10Hz to 10KHz, T _j =25°C		100		μV

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PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Supply Voltage Rejection	SVR	I _o =40mA, f=120Hz, T _j =25°C, V _{in} =5.85V, V _{ripple} =1V _{pp}	60	75		dB
Dropout Voltage	V _d	I _o =100mA		1.00	1.10	V
		I _o =500mA		1.05	1.15	V
		I _o =800mA		1.10	1.20	V
Thermal Regulation		T _a =25°C, 30ms Pulse		0.01	0.10	%/W

UTC LD1117-3.0 ELECTRICAL CHARACTERISTICS

(refer to the test circuits, T_j=0 to 125°C, C_o=10μF unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Output Voltage	V _o	V _{in} =5V, I _o =10mA, T _j =25°C	2.97	3.00	3.03	V
Output Voltage	V _o	I _o =0 to 800mA, V _{in} =4.5 to 10V	2.94		3.06	V
Line Regulation	ΔV _o	V _{in} =4.5 to 12V, I _o =0mA		1	6	mV
Load Regulation	ΔV _o	V _{in} =4.5V, I _o =0 to 800mA		1	10	mV
Temperature stability	ΔV _o			0.5		%
Long Term Stability	ΔV _o	1000 hrs, T _j =125°C		0.3		%
Operating Input Voltage	V _{in}	I _o =100mA			15	V
Quiescent Current	I _d	V _{in} ≤12V		5	10	mA
Output Current	I _o	V _{in} =8V, T _j =25°C	800	950	1200	mA
Output Noise Voltage	e _N	B=10Hz to 10KHz, T _j =25°C		100		μV
Supply Voltage Rejection	SVR	I _o =40mA, f=120Hz, T _j =25°C, V _{in} =6V, V _{ripple} =1V _{pp}	60	75		dB
Dropout Voltage	V _d	I _o =100mA		1.00	1.10	V
		I _o =500mA		1.05	1.15	V
		I _o =800mA		1.10	1.20	V
Thermal Regulation		T _a =25°C, 30ms Pulse		0.01	0.10	%/W

UTC LD1117-3.3 ELECTRICAL CHARACTERISTICS

(refer to the test circuits, T_j=0 to 125°C, C_o=10μF unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Output Voltage	V _o	V _{in} =5.3V, I _o =10mA, T _j =25°C	3.267	3.300	3.333	V
Output Voltage	V _o	I _o =0 to 800mA, V _{in} =4.75 to 10V	3.235		3.365	V
Line Regulation	ΔV _o	V _{in} =4.75 to 15V, I _o =0mA		1	6	mV
Load Regulation	ΔV _o	V _{in} =4.75V, I _o =0 to 800mA		1	10	mV
Temperature stability	ΔV _o			0.5		%
Long Term Stability	ΔV _o	1000 hrs, T _j =125°C		0.3		%
Operating Input Voltage	V _{in}	I _o =100mA			15	V
Quiescent Current	I _d	V _{in} ≤15V		5	10	mA
Output Current	I _o	V _{in} =8.3V, T _j =25°C	800	950	1200	mA
Output Noise Voltage	e _N	B=10Hz to 10KHz, T _j =25°C		100		μV
Supply Voltage Rejection	SVR	I _o =40mA, f=120Hz, T _j =25°C, V _{in} =6.3V, V _{ripple} =1V _{pp}	60	75		dB
Dropout Voltage	V _d	I _o =100mA		1.00	1.10	V
		I _o =500mA		1.05	1.15	V
		I _o =800mA		1.10	1.20	V
Thermal Regulation		T _a =25°C, 30ms Pulse		0.01	0.10	%/W

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UTC LD1117-5.0 ELECTRICAL CHARACTERISTICS

(refer to the test circuits, $T_j=0$ to 125°C , $C_o=10\mu\text{F}$ unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Output Voltage	V_o	$V_{in}=7\text{V}$, $I_o=10\text{mA}$, $T_j=25^{\circ}\text{C}$	4.95	5.00	5.05	V
Output Voltage	V_o	$I_o=0$ to 800mA , $V_{in}=6.5$ to 15V	4.90		5.10	V
Line Regulation	ΔV_o	$V_{in}=6.5$ to 15V , $I_o=0\text{mA}$		1	10	mV
Load Regulation	ΔV_o	$V_{in}=6.5\text{V}$, $I_o=0$ to 800mA		1	15	mV
Temperature stability	ΔV_o			0.5		%
Long Term Stability	ΔV_o	1000 hrs, $T_j=125^{\circ}\text{C}$		0.3		%
Operating Input Voltage	V_{in}	$I_o=100\text{mA}$			15	V
Quiescent Current	I_d	$V_{in}\leq 15\text{V}$		5	10	mA
Output Current	I_o	$V_{in}=10\text{V}$, $T_j=25^{\circ}\text{C}$	800	950	1200	mA
Output Noise Voltage	eN	$B=10\text{Hz}$ to 10KHz , $T_j=25^{\circ}\text{C}$		100		μV
Supply Voltage Rejection	SVR	$I_o=40\text{mA}$, $f=120\text{Hz}$, $T_j=25^{\circ}\text{C}$, $V_{in}=8\text{V}$, $V_{ripple}=1\text{Vpp}$	60	75		dB
Dropout Voltage	V_d	$I_o=100\text{mA}$		1.00	1.10	V
		$I_o=500\text{mA}$		1.05	1.15	V
		$I_o=800\text{mA}$		1.10	1.20	V
Thermal Regulation		$T_a=25^{\circ}\text{C}$, 30ms Pulse		0.01	0.10	%/W

UTC LD1117-ADJUSTABLE ELECTRICAL CHARACTERISTICS

(refer to the test circuits, $T_j=0$ to 125°C , $C_o=10\mu\text{F}$ unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Reference Voltage	V_{ref}	$V_{in}-V_o=2\text{V}$, $I_o=10\text{mA}$, $T_j=25^{\circ}\text{C}$	1.238	1.25	1.262	V
Reference Voltage	V_{ref}	$I_o=10$ to 800mA , $V_{in}-V_o=1.4$ to 10V	1.225		1.275	V
Line Regulation	ΔV_o	$V_{in}-V_o=1.5$ to 13.75V , $I_o=10\text{mA}$		0.035	0.200	%
Load Regulation	ΔV_o	$V_{in}-V_o=3\text{V}$, $I_o=10$ to 800mA		0.10	0.400	%
Temperature stability	ΔV_o			0.50		%
Long Term Stability	ΔV_o	1000 hrs, $T_j=125^{\circ}\text{C}$		0.3		%
Operating Input Voltage	V_{in}				15	V
Adjustment Pin Current	I_{adj}	$V_{in}\leq 15\text{V}$		60	120	μA
Adjustment Pin Current Change	ΔI_{adj}	$V_{in}-V_o=1.4$ to 10V , $I_o=10$ to 800mA		1	5	μA
Minimum Load Current	$I_o(\text{min})$	$V_{in}=15\text{V}$		2	5	mA
Output Current	I_o	$V_{in}-V_o=5\text{V}$, $T_j=25^{\circ}\text{C}$	800	950	1200	mA
Output Noise (% V_o)	eN	$B=10\text{Hz}$ to 10KHz , $T_j=25^{\circ}\text{C}$		0.003		%
Supply Voltage Rejection	SVR	$I_o=40\text{mA}$, $f=120\text{Hz}$, $T_j=25^{\circ}\text{C}$, $V_{in}-V_o=3\text{V}$, $V_{ripple}=1\text{Vpp}$	60	75		dB
Dropout Voltage	V_d	$I_o=100\text{mA}$		1.00	1.10	V
		$I_o=500\text{mA}$		1.05	1.15	V
		$I_o=800\text{mA}$		1.10	1.20	V
Thermal Regulation		$T_a=25^{\circ}\text{C}$, 30ms Pulse		0.01	0.10	%/W

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UTC LD1117-2.5C ELECTRICAL CHARACTERISTICS

(refer to the test circuits, Tj=0 to 125°C, Co=10μF unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Output Voltage	Vo	Vin=4.5V, Io=10mA, Tj=25°C	2.45	2.50	2.55	V
Output Voltage	Vo	Io=0 to 800mA, Vin=3.9 to 10V	2.40		2.60	V
Line Regulation	ΔVo	Vin=3.9 to 10V, Io=0mA		1	30	mV
Load Regulation	ΔVo	Vin=3.9V, Io=0 to 800mA		1	30	mV
Temperature stability	ΔVo			0.5		%
Long Term Stability	ΔVo	1000 hrs, Tj=125°C		0.3		%
Operating Input Voltage	Vin	Io=100mA			15	V
Quiescent Current	Id	Vin≤10V		5	10	mA
Output Current	Io	Vin=7.5V, Tj=25°C	800	950	1200	mA
Output Noise Voltage	eN	B=10Hz to 10KHz, Tj=25°C		100		μV
Supply Voltage Rejection	SVR	Io=40mA, f=120Hz, Tj=25°C, Vin=5.5V, Vripple=1Vpp	60	75		dB
Dropout Voltage	Vd	Io=100mA		1.00	1.10	V
		Io=500mA		1.05	1.15	V
		Io=800mA		1.10	1.20	V
Thermal Regulation		Ta=25°C, 30ms Pulse		0.01	0.10	%/W

UTC LD1117-3.0C ELECTRICAL CHARACTERISTICS

(refer to the test circuits, Tj=0 to 125°C, Co=10μF unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Output Voltage	Vo	Vin=5V, Io=10mA, Tj=25°C	2.94	3.00	3.06	V
Output Voltage	Vo	Io=0 to 800mA, Vin=4.5 to 10V	2.88		3.12	V
Line Regulation	ΔVo	Vin=4.5 to 12V, Io=0mA		1	30	mV
Load Regulation	ΔVo	Vin=4.5V, Io=0 to 800mA		1	30	mV
Temperature stability	ΔVo			0.5		%
Long Term Stability	ΔVo	1000 hrs, Tj=125°C		0.3		%
Operating Input Voltage	Vin	Io=100mA			15	V
Quiescent Current	Id	Vin≤12V		5	10	mA
Output Current	Io	Vin=8V, Tj=25°C	800	950	1200	mA
Output Noise Voltage	eN	B=10Hz to 10KHz, Tj=25°C		100		μV
Supply Voltage Rejection	SVR	Io=40mA, f=120Hz, Tj=25°C, Vin=6V, Vripple=1Vpp	60	75		dB
Dropout Voltage	Vd	Io=100mA		1.00	1.10	V
		Io=500mA		1.05	1.15	V
		Io=800mA		1.10	1.20	V
Thermal Regulation		Ta=25°C, 30ms Pulse		0.01	0.10	%/W

UTC LD1117-3.3C ELECTRICAL CHARACTERISTICS

(refer to the test circuits, Tj=0 to 125°C, Co=10μF unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Output Voltage	Vo	Vin=5.3V, Io=10mA, Tj=25°C	3.24	3.30	3.36	V
Output Voltage	Vo	Io=0 to 800mA, Vin=4.75 to 10V	3.16		3.44	V
Line Regulation	ΔVo	Vin=4.75 to 15V, Io=0mA		1	30	mV
Load Regulation	ΔVo	Vin=4.75V, Io=0 to 800mA		1	30	mV

UTC LD1117 LINEAR INTEGRATED CIRCUIT

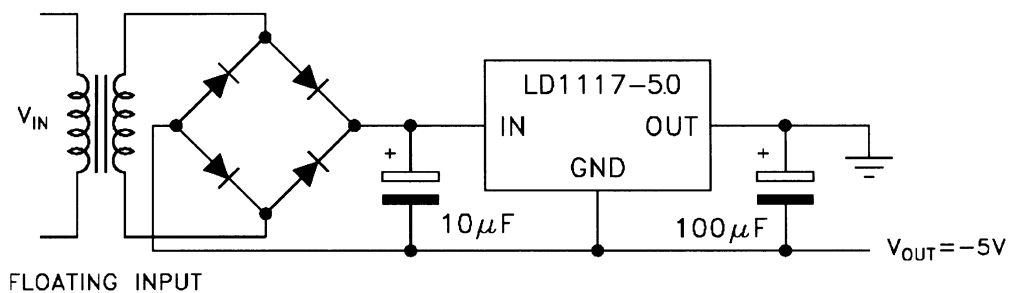
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Temperature stability	ΔV_o			0.5		%
Long Term Stability	ΔV_o	1000 hrs, $T_j=125^\circ\text{C}$		0.3		%
Operating Input Voltage	V_{in}	$I_o=100\text{mA}$			15	V
Quiescent Current	I_d	$V_{in}\leq 15\text{V}$		5	10	mA
Output Current	I_o	$V_{in}=8.3\text{V}$, $T_j=25^\circ\text{C}$	800	950	1200	mA
Output Noise Voltage	eN	B=10Hz to 10KHz, $T_j=25^\circ\text{C}$		100		μV
Supply Voltage Rejection	SVR	$I_o=40\text{mA}$, $f=120\text{Hz}$, $T_j=25^\circ\text{C}$, $V_{in}=6.3\text{V}$, $V_{ripple}=1\text{Vpp}$	60	75		dB
Dropout Voltage	V_d	$I_o=100\text{mA}$		1.00	1.10	V
		$I_o=500\text{mA}$		1.05	1.15	V
		$I_o=800\text{mA}$		1.10	1.20	V
Thermal Regulation		$T_a=25^\circ\text{C}$, 30ms Pulse		0.01	0.10	%/W

UTC LD1117-5.0C ELECTRICAL CHARACTERISTICS

(refer to the test circuits, $T_j=0$ to 125°C , $C_o=10\mu\text{F}$ unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Output Voltage	V_o	$V_{in}=7\text{V}$, $I_o=10\text{mA}$, $T_j=25^\circ\text{C}$	4.90	5.00	5.10	V
Output Voltage	V_o	$I_o=0$ to 800mA , $V_{in}=6.5$ to 15V	4.80		5.20	V
Line Regulation	ΔV_o	$V_{in}=6.5$ to 15V , $I_o=0\text{mA}$		1	50	mV
Load Regulation	ΔV_o	$V_{in}=6.5\text{V}$, $I_o=0$ to 800mA		1	50	mV
Temperature stability	ΔV_o			0.5		%
Long Term Stability	ΔV_o	1000 hrs, $T_j=125^\circ\text{C}$		0.3		%
Operating Input Voltage	V_{in}	$I_o=100\text{mA}$			15	V
Quiescent Current	I_d	$V_{in}\leq 15\text{V}$		5	10	mA
Output Current	I_o	$V_{in}=10\text{V}$, $T_j=25^\circ\text{C}$	800	950	1200	mA
Output Noise Voltage	eN	B=10Hz to 10KHz, $T_j=25^\circ\text{C}$		100		μV
Supply Voltage Rejection	SVR	$I_o=40\text{mA}$, $f=120\text{Hz}$, $T_j=25^\circ\text{C}$, $V_{in}=8\text{V}$, $V_{ripple}=1\text{Vpp}$	60	75		dB
Dropout Voltage	V_d	$I_o=100\text{mA}$		1.00	1.10	V
		$I_o=500\text{mA}$		1.05	1.15	V
		$I_o=800\text{mA}$		1.10	1.20	V
Thermal Regulation		$T_a=25^\circ\text{C}$, 30ms Pulse		0.01	0.10	%/W

TYPICAL APPLICATIONS



UTCLD1117 LINEAR INTEGRATED CIRCUIT

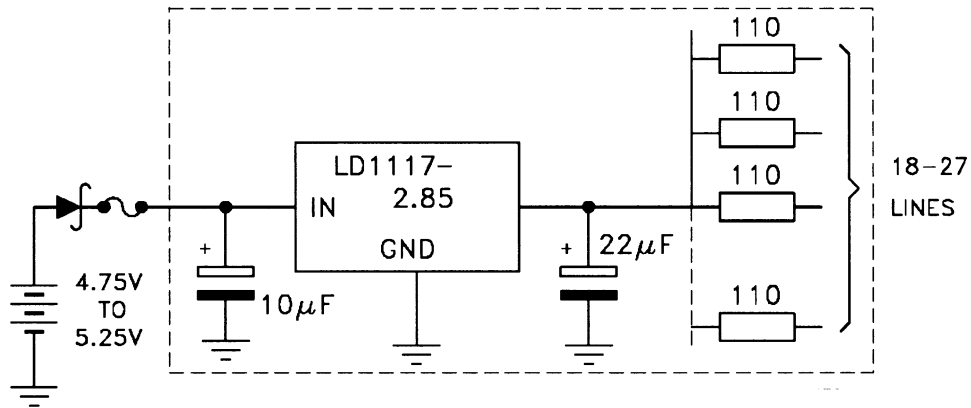


FIG.2 Active Terminator for SCSI-2 BUS

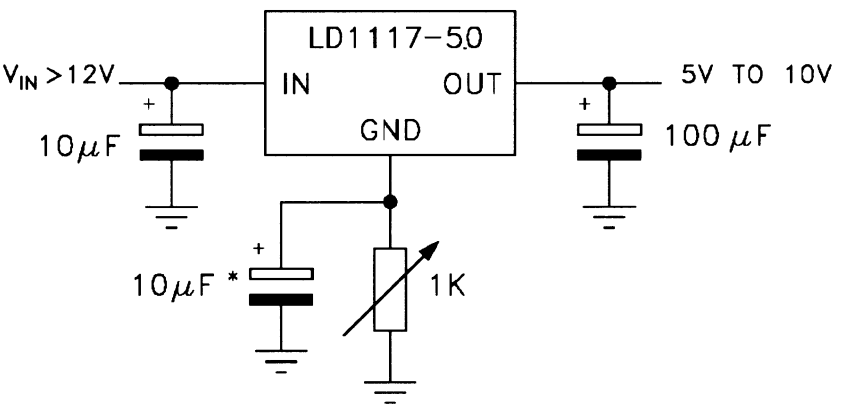


FIG.3 Circuit for Increasing Output Voltage

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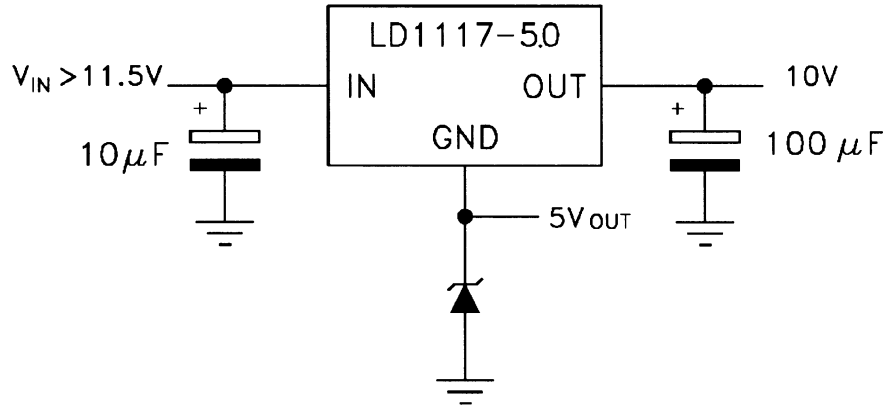


FIG.4 Voltage Regulator With Reference

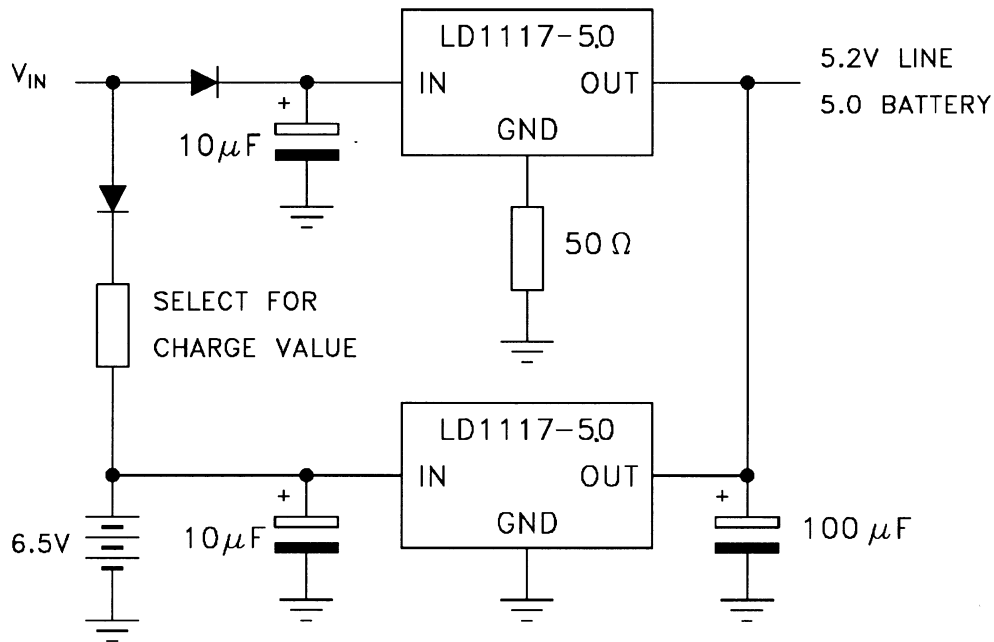


FIG.5 Battery Backed-up Regulated Supply

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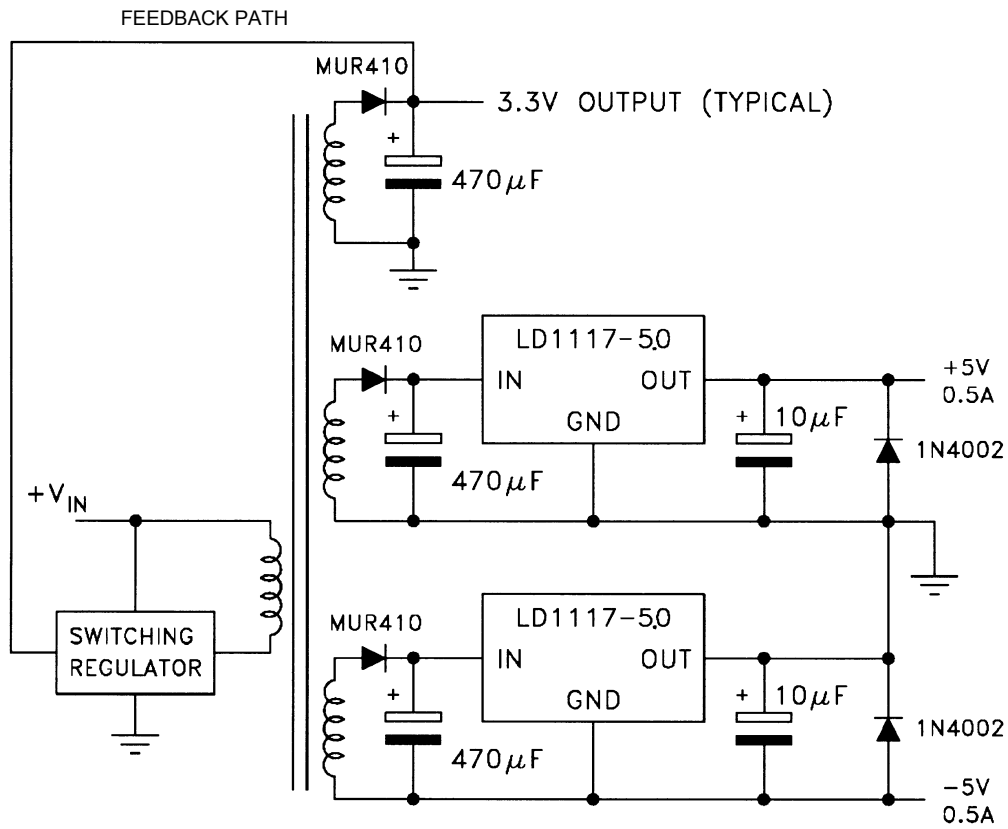


FIG.6 Post-Regulated Dual Supply

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LD1117 ADJUSTABLE APPLICATION NOTE

The LD1117 ADJUSTABLE has a thermal stabilized $1.25 \pm 0.012V$ reference voltage between the OUT and ADJ pins.

I_{ADJ} is $60\mu A$ typ. ($120\mu A$ max.) and ΔI_{ADJ} is $1\mu A$ typ. ($5\mu A$ max.).

$R1$ is normally fixed to 120Ω . From figure 7 we obtain:

$$V_{OUT} = V_{REF} + R2(I_{ADJ} + I_{R1}) = V_{REF} + R2(I_{ADJ} + V_{REF} / R1) = V_{REF}(1 + R2/R1) + R2 \times I_{ADJ}$$

In normal application $R2$ value is in the range of few Kohm., so the $R2 \times I_{ADJ}$ product could not be considered in the V_{OUT} calculation; then the above expression becomes: $V_{OUT} = V_{REF}(1 + R2/R1)$

In order to have the better load regulation it is important to realize a good Kelvin connection of $R1$ and $R2$ resistors.

In particular $R1$ connection must be realized very close to OUT and ADJ pin, while $R2$ ground connection must be placed as near as possible to the negative Load pin. Ripple rejection can be improved by introducing a $10\mu F$ electrolytic capacitor placed in parallel to the $R2$ resistor (See Fig. 8)

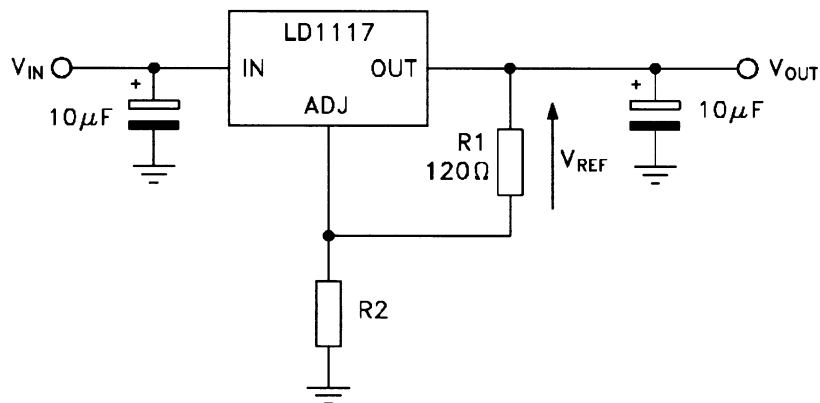


FIG.7 Adjustable Output Voltage Application Circuit

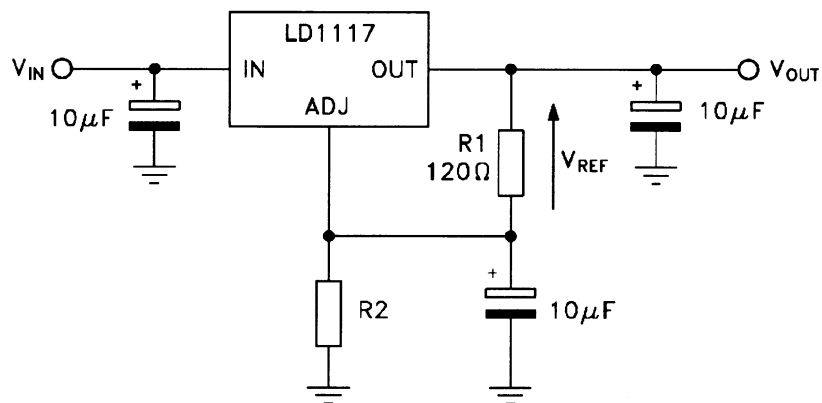


FIG.8 Adjustable Output Voltage Application with improved Ripple Rejection.